NEUTRON DAMAGE, TRAPPING AND CORRECTION



Det. 1B - Shape of the 1332 keV line



White: April 2010 → FWHM(core) ~ 2.3 keV FWHM(segments) ~2.0 keV Green: July 2010 → FWHM(core) ~2.4 keV FWHM(segments) ~2.8 keV Damage after 3 high-rate experiments (3 weeks of beam at 30-80 kHz singles)

Worsening seen in most of the detectors; more severe on the forward crystals; segments are the most affected, cores almost unchanged (as expected for n-type HPGe)

Crystal 1B (COO2)

April 2010









The 1332 keV peak as a function of crystal depth (z) for interactions at r = 15mm

The charge loss due to neutron damage is proportional to the path length to the electrodes. This is provided by the PSA, which is barely affected by the amplitude loss.

Knowing the interaction position,

the charge trapping can be modeled and corrected away

Trapping cross sections



L. Reggiani – Rev. del Nuovo Cimento 12 nr 11 (1989)

Most popular is model by Lax: Cross sections are field dependent -Cross sections are **velocity** dependent e.g. Poole – Frenkel effect electron eneray condúction Γ_{Δ} band Lax: cascade model E, 1) electron emits phonon near trap center U(r)2) electron in interaction with phonon field: or: struggles out of trap Sticking or: collapses to ground state probability trap ground state - E (0) I But also other (recent) models exist: 0.6 e.g. L. S. Darken – PRL 69 (1992) 19 p 2842 0.5 hole velocity after Pinson and Bray Vd / V_{rms} 0.4 $<\sigma v>\propto E^x < v^y>$ Ge <111> 0.3 T = 77°K 0.2 $p = 1.9 \times 10^{15} / cm^3$ only data •data on <v^y> basically not existing 0.1 difficult to know which model to use 0 1000 1500 2000 500 ELECTRIC FIELD STRENGTH (V/cm)

Trapping cross section: neutron damage specific

L. S. Darken et al. NIM 171 (1980)



Cross section from field line disturbance:

Balance between E field and Coulomb force:



Assumptions:

- Trapping only by disordered regions
- •Macroscopic model: drift velocity!
- Q ~ 100e equilibrium charge state
- r_{max} ~ 2 μ m cross section (E=2kV/cm)
- $I_e\,{\sim}\,0.2\;\mu m\,$ dist. betw. optical phonon emission

used:
$$<\sigma v>\propto rac{v_d}{E}$$

Some theory: collection efficiency

T.W. Raudorf, R. H. Pehl – NIM A 255 (1987) 538-551

•Trapping rate of electrons / holes "q":

$$\frac{dq}{dt} = - <\sigma \, v > N_t q \quad \Leftrightarrow \quad q(t) = q_0 \cdot e^{-\int_0^t <\sigma v > N_t dt'}$$

- $\sigma\,$: trapping cross section
- v : microscopic velocity
- <.>: average over ensemble
- N_t : density of trapping centers

•Collection efficiency (position dependent) of electrons / holes for electrode "i":

$$\eta_{e,h}^i(\vec{x}_0) = -\int_0^{t_e} \left(\vec{\nabla}\phi_i \cdot \vec{v}_{e,h}\right) \cdot \frac{q(t)}{q_0} dt$$

- $\mathbf{x}_{0}~$: interaction position in detector
- $\varphi_i \;$: weighting potential of segment i
- $\boldsymbol{v}_{e,h}$: drift velocity of electrons / holes
- $\mathbf{t}_{\mathrm{e}}~$: collection time
- Integral [current to seg i per unit charge]
- = total recorded charge by e/h after collection

•Total collection efficiency for electrode "i" at position x₀ :

$$\begin{split} \eta_{tot}^i(\vec{x}_0) &= \eta_e^i(\vec{x}_0) + \eta_h^i(\vec{x}_0) \\ & \checkmark \\ & \simeq \phi_i(\vec{x}_0) + [1 - \phi_i(\vec{x}_0)] \cong 1 \end{split}$$

Partial collection efficiencies mainly report on weighting potential

Trapping sensitivity*



(*personal definition – don't google!)

•DEFINITION: electron / hole sensitivity of electrode i to trapping

$$s_{e,h}^i = \frac{d\eta_{e,h}^i}{dN_t} \mid_{N_t=0}$$

= fraction missing due to trapping

+ induced charge due to trail of trapped charges

•Relation to total collection efficiency:

$$\eta_{tot}^{i}(\vec{x}_{0}) = 1 + \left[N_{e} s_{e}^{i}(\vec{x}_{0}) + N_{h} s_{h}^{i}(\vec{x}_{0}) \right] + O(2)$$

•Ne : density of electron traps, Nh: density of hole traps
•O(2) – higher order terms in taylor expansion - negligible
•sensitivities can be calculated in advance
•Ne . Nh are fit percentators

•Ne, Nh are fit parameters







Trapping in <u>new</u> detectors

•Electron trapping present in any detector •Source of scattering on Fano factors











Correction of neutron damage

 $\eta_{tot}^{i}(\vec{x}_{0}) = 1 + \left[N_{e} s_{e}^{i}(\vec{x}_{0}) + N_{h} s_{h}^{i}(\vec{x}_{0}) \right]$



The 1332 keV peak as a function of crystal depth (z) for interactions at r = 15mm (worst case !)









• For a fixed position x₀ in the detector, the # trapped charges varies evt by evt:

 $\sigma(\vec{x}_0) = \sqrt{\sigma_N^2 + \sigma_F^2 + \sigma_T(\vec{x}_0)^2}$

• The variation in trapped charges behaves Fano-alike:

 $\sigma_T(\vec{x}_0) = \sqrt{\varepsilon K E_0 [1 - \eta(\vec{x}_0)]}$

• K is a value, which seems to depend on the type of trapping. We propose:

 $\sigma(\vec{x}_0)_T = \sqrt{\epsilon E_0 |K_e N_e s_e^i(\vec{x}_0) + K_h N_h s_h^i(\vec{x}_0)|}$

• K measured from our observation:

Energy [keV]	σ_0 [keV]	K_h
1332	2.02	300
1172	1.95	284

 Kh in agreement with T.W. Raudorf et al., Ke is about 60 ! (see Thesis Wiens (IKP 2010)

Summary

- AGATA : best data ever to investigate trapping!
- Segments (AGATA) more sensitive than core electrode
- Neutron damage confirms PSA principle (and PSA works also in neutron damaged detectors)
- First results promising with simple assumptions
 →simple 2 parameter fit
- Limits on the correction capability established: $K_h = 300, K_e = 60$
- Correction method alows anealing of detectors

